

<b>Notice of References Cited</b>	Application/Control No. 10/705,863		Applicant(s)/Patent Under Reexamination HIBINO ET AL.	
	Examiner Duc M. Nguyen		Art Unit 2685	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,933,984 B2	08-2005	Yamamoto et al.	348/731
*	B	US-6,472,953 B1	10-2002	Sakuragawa et al.	333/133
*	C	US-5,917,387 A	06-1999	Rice et al.	333/174
*	D	US-4,153,887	05-1979	Poppa, Rocco	333/172
*	E	US-5,054,117	10-1991	Cruz et al.	455/188.2
*	F	US-5,463,362 A	10-1995	Kitaguchi, Masanori	334/47
*	G	US-5,978,663	11-1999	Yamamoto, Masaki	455/193.2
*	H	US-4,607,391	08-1986	Matsuda, Shigetoshi	455/188.2
*	I	US-6,903,783 B2	06-2005	Yamamoto, Masaki	348/731
*	J	US-6,864,924 B2	03-2005	Yamamoto, Masaki	348/731
*	K	US-4,596,044	06-1986	Aoki et al.	455/189.1
*	L	US-4,731,877	03-1988	Moon, Fredrick H.	455/340
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0829918 A2	08-1997	EP	Camacho	H01Q 1/28
	O	JP2001359005 A	12-2001	JP	Yoda et al	H04N 005/44
	P	JP354104219 A	08-1979	JP	Shinagawa et al	H04B 001/18
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.